

IndustryNews

NanoInk Installs New Nanofabrication System at the University of Strathclyde's Centre for Molecular Nanometrology

The Centre for Molecular Nanometrology at the University of Strathclyde has taken delivery of the DPN 5000 nanolithography tool, NanoInk's latest high-precision Dip Pen Nanolithography® (DPN®) system. Combining high-resolution lithography with world-class imaging capability, the new instrument will expand the group's already formidable nanotechnology toolkit and help Graham move towards *in vivo* imaging approaches based on functional nanoparticles and SERS analysis.

NanoInk, Inc.
www.nanonink.net

Olympus Canada to distribute the new Hitachi TM3000 Table Top SEM

Olympus Canada Inc. and Hitachi High-Technologies Canada have announced a new partnership making Olympus the exclusive distributor of the new TM3000 Table Top Scanning Electron Microscope (SEM) in Canada. The TM3000 offers a dramatic improvement in all the features of the earlier TM-1000 device and is expected to have an immediate impact in areas ranging from R&D to quality assurance in a host of fields.

Olympus Canada, Inc.
www.olympuscanada.com

Helium-Ion Microscopy Fires the Imagination of Researchers in U.S. and Japan

The Pacific Northwest National Laboratory, located in Richland, Washington, is bringing an ORION® PLUS instrument into the U.S. Department of Energy's Environmental Molecular Sciences Laboratory as a resource. And, in Tsukuba, Japan, the National Institute of Advanced Industrial Science and Technology has selected an ORION PLUS for their new Nanodevice Innovation Research Center. These installations provide further evidence of a growing reliance on helium-ion microscopy for the most demanding research.

Carl Zeiss SMT
www.zeiss.com

JEOL Microprobe Helps Students and Industry in North Carolina



The installation of a JEOL Electron Probe Microanalyzer (EPMA) will expand research and educational opportunities for students, faculty, and industry in southeastern North Carolina. In January, JEOL completed the installation of its new generation of EPMA at the Southeastern North Carolina Regional Microanalytical and Imaging Center (SENCR-MIC), a state-of-the-art facility opened in 2009 as a joint collaboration between Fayetteville State University and the University of North Carolina at Pembroke.

JEOL USA, Inc.
www.jeolusa.com

Yale University Selects Vistec EBP5000plus Electron-Beam Lithography System for Advanced Nanotechnology Research

Vistec Lithography, Inc. announced today that Yale University, New Haven, Conn., selected Vistec's EBP5000plus electron-beam lithography system for its future nanotechnology research programs. As part of the Yale Institute for Nanoscience and Quantum Engineering, it will enhance the effectiveness of research and education at Yale in emerging nanotechnology and will encourage multidisciplinary research involving Yale faculty, its students, and associated worldwide research partners.

Vistec Lithography, Inc.
nano.yale.edu

NIKON forms NIKON METROLOGY, INC. For Industrial-Based Metrology Customers

Nikon today announced that it has formed Nikon Metrology, Inc., a new company that combines Nikon Instruments Inc.'s industrial instruments business with the former Metris business, acquired by Nikon Corp. in 2009. Nikon Metrology, Inc., headquartered in Brighton, Mich., will focus specifically on the industrial and manufacturing business markets for precision measuring and industrial microscopy.

Nikon, Inc.
www.nikonmetrology.com

Bruker AXS Microanalysis is Now Bruker Nano

Bruker AXS Microanalysis has changed its name to Bruker Nano. The name change was motivated by the ever-increasing applications of the company's traditional products, such as EDS and EBSD analysis systems for electron microscopes and X-ray fluorescence spectrometers in various fields of nanotechnology, and also by the fact that the company's product portfolio now includes a range of atomic force microscopes (AFM) for surface characterization on the nanometer and sub-nanometer scale.

Bruker Nano
www.bruker-nano.com

FEI Completes Multiple System Installation at Materials Ageing Institute Research Center in France



FEI Company announces the completion of a multiple system installation at the Materials Ageing Institute (MAI) in France. The MAI microscopy laboratory has now commissioned its new FEI Titan™ S/TEM microscope, which joins the MAI's FEI Tecnai™ S/TEM, Helios DualBeam™ and Quanta™ 600 FEG in one of the world's premier microscopy facilities. They will be used to study the aging of materials to improve the reliability and safety, and extend the lifetimes, of nuclear and non-nuclear power plants.

FEI Company
www.fei.com